第228回触媒化学研究センター談話会

演 題 ： Characterization of Complex Oxides using Advanced Diffraction and Imaging Techniques

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場所：北海道大学創成科学研究棟 4 階セミナー室 A

要旨：

Two examples of complex oxide structural and compositional analysis will be used to illustrate the capabilities of modern diffraction and imaging techniques. The first case will be that of layered perovskites of the type $Ln_{2-x}Sr_xNiO_{4+\square}$ (where *Ln* = La, Pr, Nd, ... and Y), which are of interest both as model systems for understanding strongly correlated 2D electron systems and as potential fuel cell materials. The second example will involve the Mo-V-(Nb,Ta)-Te-O materials that are of interest for alkane selective oxidation and ammoxidation. High resolution TEM and STEM methods, including aberration-corrected HAADF-STEM, will be used in combination with x-ray and neutron diffraction for the analysis of these challenging materials systems.

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